MT3205B

N-Channel Power MOSFET 60V, 140A, 3.6m Ω

General Description

This N-channel MOSFET is produced using MOS-TECH Semiconductor's advanced PowerTrench process that has been especially tailored to minimize the on-state resistance and yet maintain superior switching performance.

Features

- R $_{DS(on)}$ = 3.6m Ω (Typ.)@ V_{GS} = 10V, I_{D} = 100A
- High performance trench technology for extremely low RDS(ON)
- · High power and current handling capability
- · RoHS compliant

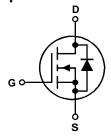
Applications

DC/DC converters



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Simplified Schematic



MARKING DIAGRAM & PIN ASSIGNMENT



TO-263-2L

Absolute Maximum Ratings(TA = 25°C unless otherwise noted)

Symbol	Parameter			Ratings	Units
V_{DSS}	Drain to Source Voltage	Drain to Source Voltage			V
V_{GSS}	Gate to Source Voltage	Gate to Source Voltage		±20	V
I _D	Drain Current	-Continuous (T _C = 25°C)	(Note 1)	140	А
I _{DM}	Drain Current	- Pulsed		470	Α
E _{AS}	Single Pulsed Avalanche Energy (Note		(Note 2)	397	mJ
P_{D}	Power Dissipation	(T _C = 25°C)		250	W
		- Derate above 25°C		1.0	W/°C
T_J, T_{STG}	Operating and Storage Temperature Range			-55 to +175	°C

Thermal Characteristics

Symbol	Parameter	Ratings	Units
$R_{\theta JC}$	Thermal Resistance, Junction to Case	0.65	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient	35	-C/VV

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Flectrical Characteristics

Symbol	Parameter	Test Conditions		Min.	Тур.	Max.	Units
Off Charac	cteristics						
BV _{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V,$	60	-	-	V	
	Zero Gate Voltage Drain Current $\frac{V_{DS} = 44V, V_{GS} = 0V}{V_{DS} = 44V, T_{C} = 150^{\circ}C}$			-	-	25	μА
IDSS			C	-	-	250	
I _{GSS}	Gate to Body Leakage Current	$V_{GS} = \pm 20V, V_{DS} = 0V$		-	-	±100	nA
On Charac	cteristics						
V _{GS(th)}	Gate Threshold Voltage	VGS = VDS, ID = 250μA		2		4	V
00(11)		V _{GS} = 10V, I _D = 100A		-	3.6	4. 5	
R _{DS(on)}	Static Drain to Source On Resistance	V _{GS} = 10V, I _D = 56A T _J = 175°C		-	10	-	mΩ
Dynamic (Characteristics						
C _{iss}	Input Capacitance	V _{DS} = 25V, V _{GS} = 0V f = 1MHz		-	3520	4360	pF
C _{oss}	Output Capacitance			-	550	760	pF
C _{rss}	Reverse Transfer Capacitance			-	340	470	pF
R _G	Gate Resistance	V _{GS} = 0V, f = 1MHz		3	4	5	Ω
Q _{g(tot)}	Total Gate Charge at 10V	V _{GS} = 0V to 10V		-	121	145	nC
Q _{g(th)}	Threshold Gate Charge	V _{GS} = 0V to 2V	V _{DS} = 44V	-	35	46	nC
Q _{gs}	Gate to Source Gate Charge		$I_{D} = 59A$	-	45	-	nC
Q _{gs2}	Gate Charge Threshold to Plateau		$I_g = 1mA$		18	-	nC
Q_{gd}	Gate to Drain "Miller" Charge			-	39	-	nC
Switching	Characteristics						
t _{ON}	Turn-On Time			-	99	137	ns
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 28V, I_D = 59A$ $V_{GS} = 10V, R_{GEN} = 2.5\Omega$		-	19	38	ns
t _r	Turn-On Rise Time			-	127	251	ns
t _{d(off)}	Turn-Off Delay Time			-	47	73	ns
t _f	Turn-Off Fall Time			-	19	49	ns
t _{OFF}	Turn-Off Time			-	67	89	ns
Drain-Sou	rce Diode Characteristics						
V _{SD}	Drain to Source Diode Forward Voltage	V _{GS} = 0V, I _{SD} = 59A		-	-	1.2	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0V, I_{SD} = 59A$ $dI_F/dt = 100A/\mu s$		-	49	-	ns
Q _{rr}	Reverse Recovery Charge			-	78	-	nC

2

Q_{rr}

Notes:
 1: Calculated continuous current based on maximum allowable junction temperature. Package limited to 75A continuous, see Figure 9.
 2: L = 0.21mH, I_{AS} = 59A, V_{DD} = 50V, V_{GS} = 10V, R_G = 25Ω, Starting T_J = 25°C

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Typical Performance Characteristics

Figure 1. On-Region Characteristics

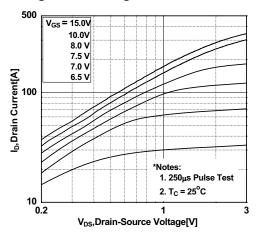


Figure 3. On-Resistance Variation vs.

Drain Current and Gate Voltage

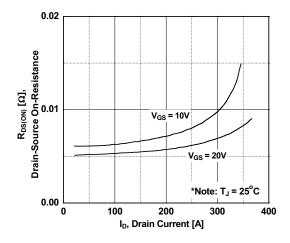


Figure 5. Capacitance Characteristics

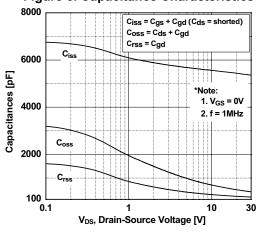


Figure 2. Transfer Characteristics

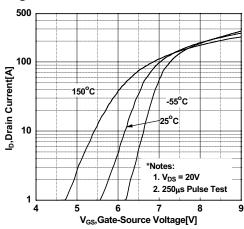


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

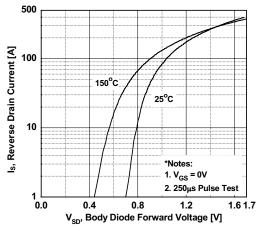
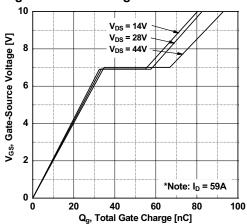


Figure 6. Gate Charge Characteristics



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Typical Performance Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

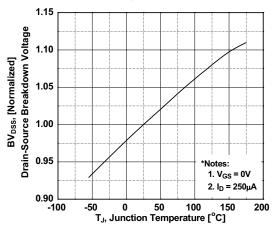


Figure 9. Maximum Safe Operating Area

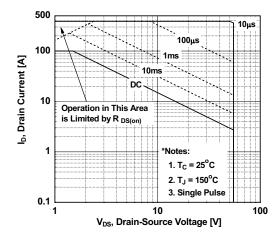


Figure 8. On-Resistance Variation vs. Temperature

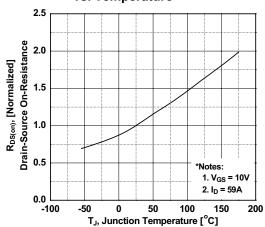


Figure 10. Maximum Drain Current vs. Case Temperature

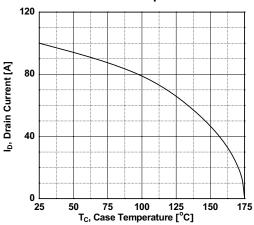
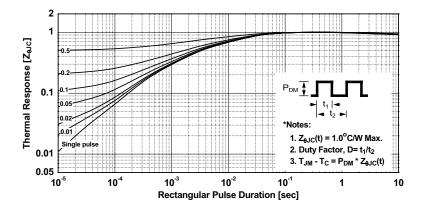
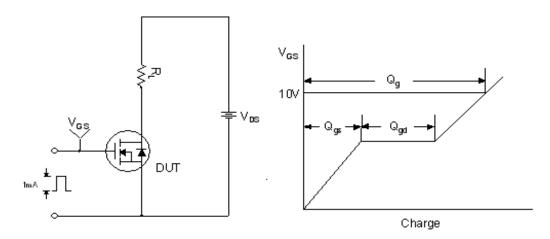


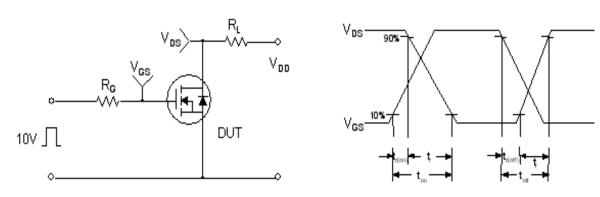
Figure 11. Transient Thermal Response Curve



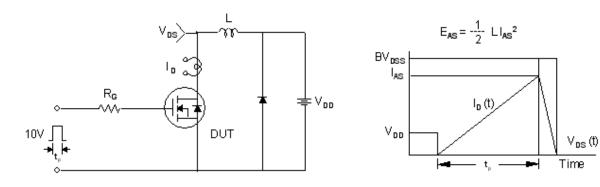
Gate Charge Test Circuit & Waveform



Resistive Switching Test Circuit & Waveforms

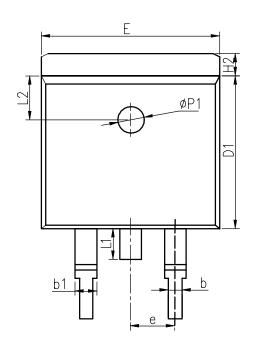


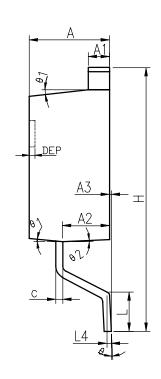
Unclamped Inductive Switching Test Circuit & Waveforms

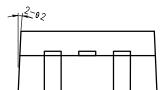


Peak Diode Recovery dv/dt Test Circuit & Waveforms DUT **╞** V ₀ ₀ ∏∏ V G S \bullet dv/dt controlled by R $_{\text{G}}$ \bullet I_{SD} controlled by pulse period Gate Pulse Width Gate Pulse Period V _{G S} 1 0 V (Driver) I_{FM} , Body Diode Forward Current Isp d i/d t (DUT) Body Diode Reverse Current V_{DS} (DUT) Body Diode Recovery dv/dt Body Diode Forward Voltage Drop

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COMMON DIMENSIONS

SYMBOL	MM			INCH			
	MIN	NOM	MAX	MIN	NOM	MAX	
Α	4.40	4.57	4.70	0.173	0.180	0.185	
A1	1.22	1.27	1.32	0.048	0.050	0.052	
A2	2.59	2.69	2.79	0.102	0.106	0.110	
A3	0.00	0.10	0.20	0.000	0.004	0.008	
b	0.77	0.813	0.90	0.030	0.032	0.035	
b1	1.20	1.270	1.36	0.047	0.050	0.054	
С	0.34	0.381	0.47	0.013	0.015	0.019	
D1	8.60	8.70	8.80	0.339	0.343	0.346	
E	10.00	10.16	10.26	0.394	0.400	0.404	
E2	10.00	10.10	10.20	0.394	0.398	0.402	
е	2.54 BSC				0.100 BSC		
Н	14.70	15.10	15.50	0.579	0.594 0.610		
H2	1.17	1.27	1.40	0.046	0.050	0.055	
L	2.00	2.30	2.60	0.079	0.091	0.102	
L1	1.45	1.55	1.70	0.057	0.061 0.067		
L2	2.50 REF				0.098 REF		
L4	0.25 BSC			0.010 BSC			
	0°	5°	8°	0°	5°	8°	
1	5°	7°	9°	5°	7°	9°	
2	1°	3°	5°	1°	3°	5°	
ФР1	1.40	1.50	1.60	0.055	0.059	0.063	
DEP	0.05	0.10	0.20	0.002	0.004	0.008	

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